Supplementary Information

Microstructure analysis of complex CuO/ZnO@carbon adsorbers: What are the limits of powder diffraction methods?

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Diffraction

For pure CuO synchrotron data have been collected at ESRF (ID15B) in transmission geometry using a wavelength of 0.143165 Å. The final fit obtained from WPPM is shown in Figure S1(a), the comparison of the domain size distributions is shown in Figure S1(b).

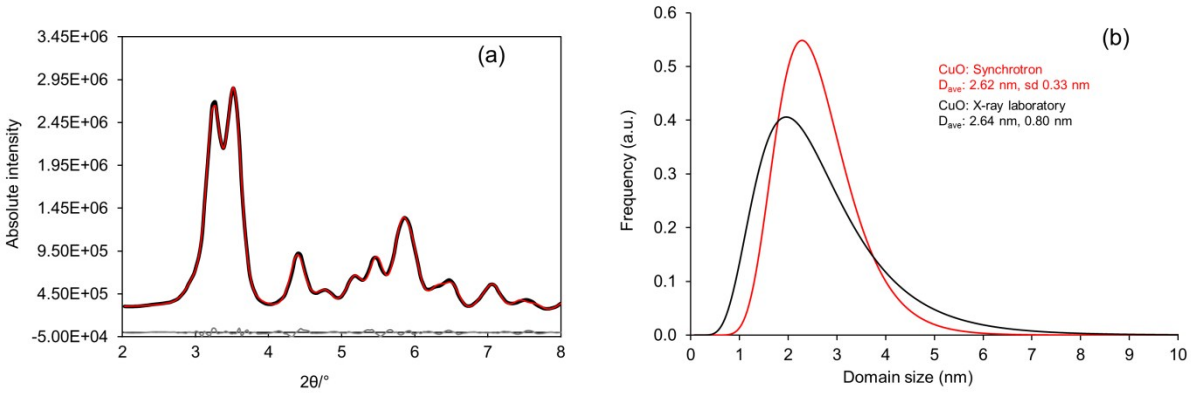

Figure S1: (a) WPPM results obtained for pure CuO. Experimental data measured black line, modeled profile: red line, difference plot: gray line. (b) Domain size distributions obtained for the pure crystalline compound from synchrotron and laboratory data.

X-Ray Photoelectron Spectroscopy

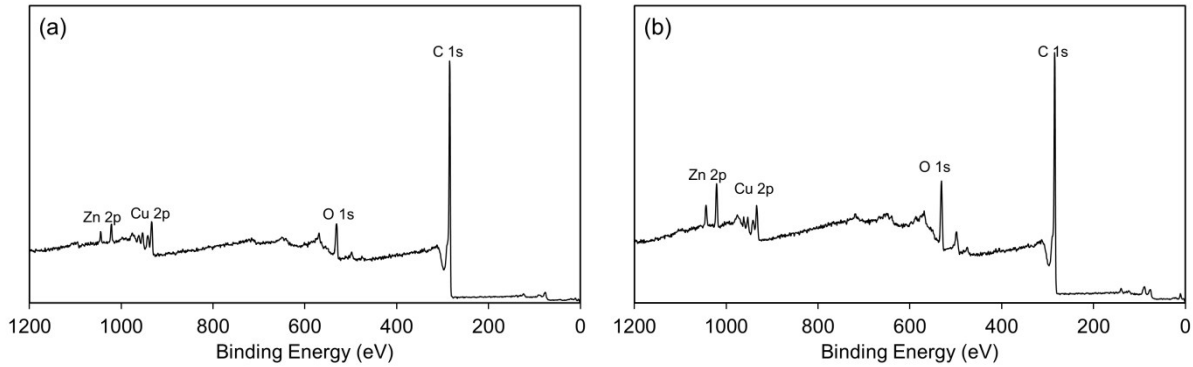

Figure S2: XPS survey scan obtained for the real catalyst (a) before and (b) after NO_2 removal experiments.